

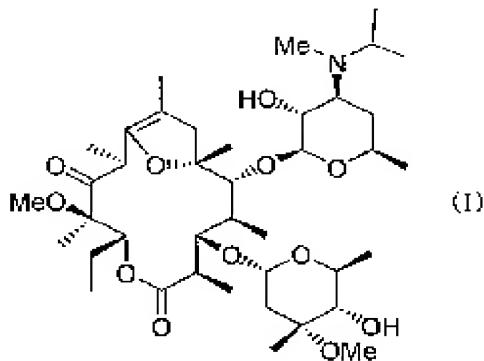
**AMENDMENTS TO THE CLAIMS:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

**Listing of Claims:**

**1-24. (Cancelled)**

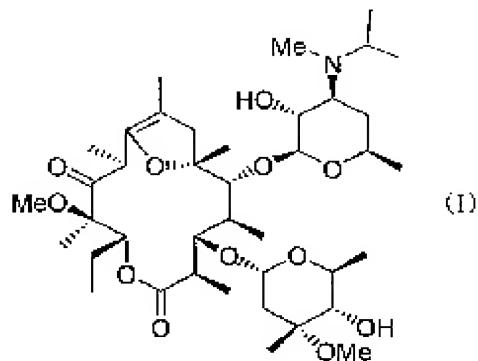
**25. (Currently Amended)** A process for preparing a hemifumarate anhydride of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, and a residual solvent content of 1500 ppm or below, said process comprising:

treating Crystal Form C at 20-40°C in a mixed solvent of ethyl acetate and water to obtain Crystal Form E, and

stirring the Crystal Form E in a mixed solvent of ethyl acetate and water at less than 20°C to obtain a hemifumarate crystal of a compound of formula (I):

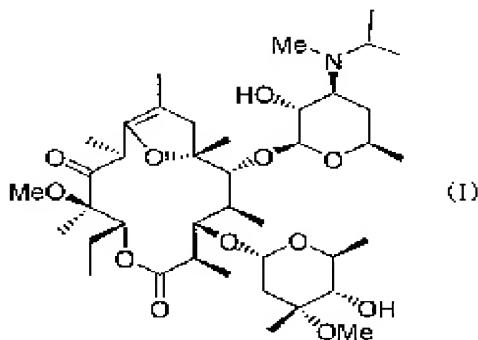


characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°, and

drying the hemifumarate crystal under reduced pressure to obtain said hemifumarate anhydrate,

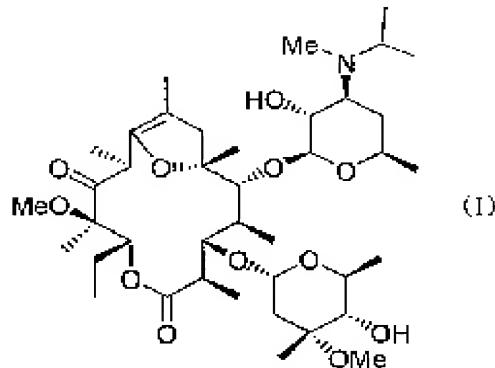
wherein Crystal Form E is a hemifumarate ~~hydrate~~ of a compound formula (I) that has 2-theta angle positions in the powder X-ray diffraction patterns of 5.6° and 10.4° as measured by X-ray diffractometry.

**26. (Currently Amended)** Crystal Form of a hemifumarate anhydrate of a compound of formula (I):



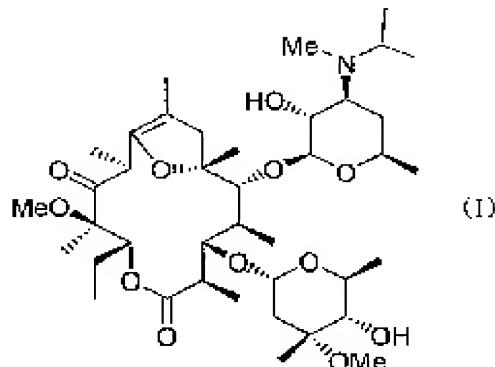
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, and a residual solvent content of 1500 ppm or below, which crystal is obtained by the process of claim 25.

**27. (Currently Amended)** A process for preparing a hemifumarate hydrate of a compound of formula (I):



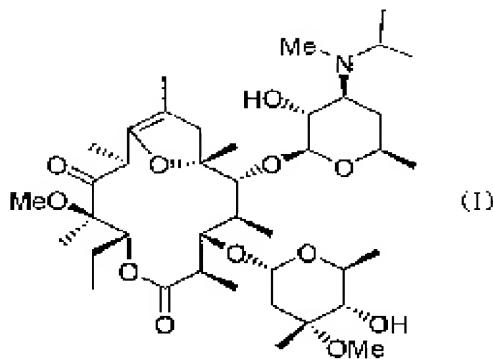
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, and a residual solvent content of 1500 ppm or below, said process comprising:

stirring Crystal Form E in a mixed solvent of ethyl acetate and water to obtain a hemifumarate crystal of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction patterns-pattern of 6.6° and 8.5°, and

drying the hemifumarate crystal under reduced pressure to obtain a hemifumarate anhydrate of a compound of formula (I):

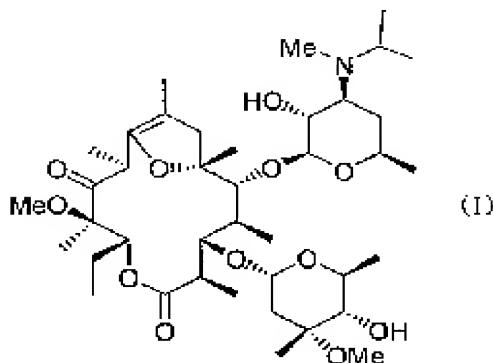


characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, and

conditioning the anhydrate to obtain said hemifumarate hydrate;

wherein Crystal Form E is a hemifumarate hydrate of a compound of formula (I) that has 2-theta angle positions in the powder X-ray diffraction pattern of 5.6° and 10.4° as measured X-ray diffractometry.

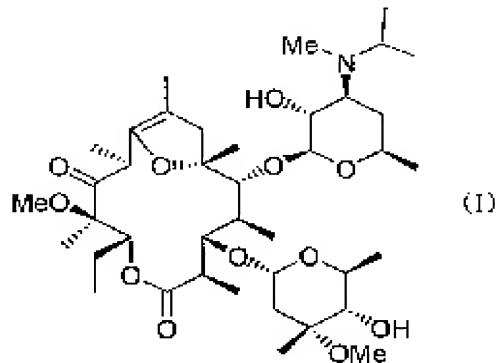
**28. (Currently Amended) A-Crystal Form of a hemifumarate hydrate of a compound of formula (I):**



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, and a residual solvent content of 1500 ppm or below, which crystal is obtained by the process of claim 27.

**29-34. (Cancelled)**

**35. (Currently Amended)** Crystal Form D of a hemifumarate hydrate of a compound of formula (I):



which crystal is obtained via Crystal Form E and a residual solvent content of 1500 ppm or below,

wherein Crystal Form E is a hemifumarate ~~hydrate~~ of a compound of formula (I) that has 2-theta angle positions in the powder X-ray diffraction pattern of 5.6° and 10.4° as measured X-ray diffractometry.